Deep/Machine Learning in Visual Recognition and Anomaly Detection

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Message from the Guest Editors

Dear Colleagues，

Conventional learning-based visual semantic recognition approaches rely heavily on large-scale training data with dense annotations and consistently fail to estimate accurate semantic labels for unseen categories. The emergence of few-/zero-shot learning make it possible to learn unseen categories from a few labeled or even zero-labeled samples, which advances the extension to practical applications. The editors hope to collate a group of research results to report the recent developments in the related research topics. In addition, researchers can exchange their innovative ideas on the topic of few-/zero-shot learning in visual recognition and anomaly detection by submitting manuscripts for this Special Issue.

In this Special Issue, original research articles and reviews are welcome. Research areas may include (but are not limited to) the following:

(1) Theoretical advances and algorithm developments in few-/zero-shot learning;

(2) Useful applications of few-/zero-shot learning in visual recognition and anomaly detection;

(3) New datasets and benchmarks for few-/zero-shot learning in visual recognition and anomaly detection.

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Special Issue

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Message from the Editor-in-Chief

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